

**Search Notes**

Application/Control No.

10/623,552

Examiner

Devin Hanan

Applicant(s)/Patent under  
Reexamination

LIN, FAN-YEE

Art Unit

3745

**SEARCHED**

Class	Subclass	Date	Examiner
416	223R		
	210R		
	5		
D23	413	4/25/2005	DH

**INTERFERENCE SEARCHED**

Class	Subclass	Date	Examiner

**SEARCH NOTES  
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
consulted Chris Verdier on class 416	4/21/2005	DH